## **Application Examples and Components Selection**

Figures 9 and 10 show the schematic layout and typical components required for correct usage of the SCALE-iDriver. In both cases the primary- side supply voltage ( $\rm V_{vcc})$  is connected between VCC – GND and

supported through a blocking ceramic capacitor C1 (100 nF). Input signal logic is 15 V and it is connected to the IN pin through a resistive voltage driver and Schmitt trigger gates. The SO output has 5 V logic and the  $\rm R_{so}$  is selected so that it does not to exceed  $\rm I_{so}.$ 

The secondary insulated power supply (V<sub>TOT</sub>) is connected between VISO and COM. The positive voltage rail (V<sub>VISO</sub>) is supported through 4.7 µF ceramic capacitors C<sub>S21</sub> – C<sub>S22</sub> connected in parallel. The negative voltage rail (V<sub>VEE</sub>) is similarly supported capacitors C<sub>S11</sub> – C<sub>S12</sub>. Depending on the type of semiconductor that is being driven, the gate charge is different. Typically, the V<sub>VISO</sub> and V<sub>VEE</sub> blocking capacitors should have a minimum value calculated as 3 µF per every 1 µC of gate charge. A ceramic capacitor C<sub>GXX</sub> with value of 10 nF is connected to the GH pin.

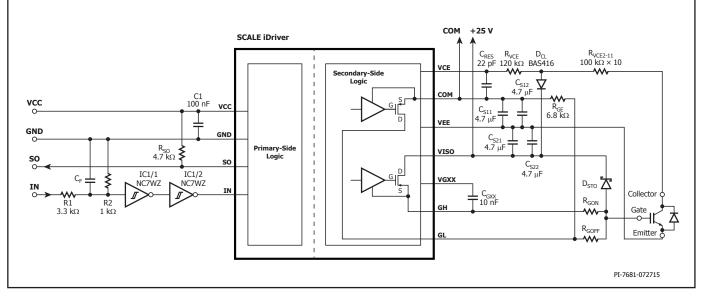


Figure 9. SCALE-iDriver Application Example using a Resistor Chain for Desaturation Detection.

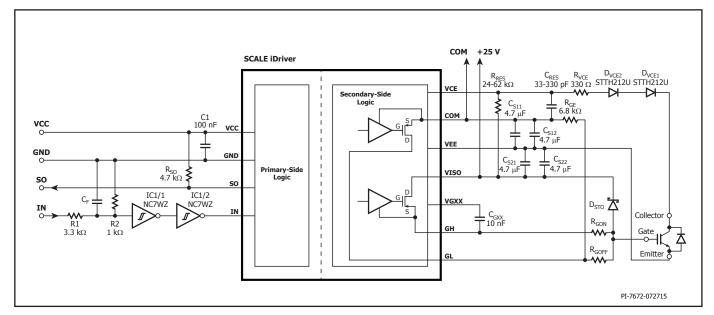


Figure 10. SCALE-iDriver Application Example using Diodes for Desaturation Detection.



Example Components & Layout The gate of the semiconductor being driven is connected through resistor  $\rm R_{GON}$  to the GH pin and  $\rm R_{GOFF}$  to the GL pin. If the value of  $\rm R_{GON}$  is the same as  $\rm R_{GOFF}$  the GH pin can be connected to the GL pin and the gate resistor can beconnected to the gate. In each case, proper consideration needs to be given to the power dissipation and temperature performance of the gate resistor.

To ensure gate voltage stabilization and collector current limitation during a short-circuit, the gate is connected to  $V_{_{\rm ISO}}$  through Schottky diode  $D_{_{\rm STO}}$  (for example PMEG4010).

To avoid parasitic power switch conduction during system power-on, the gate is connected to COM through 6.8  $k\Omega$  resistor.

Figure 9 shows how semiconductor desaturation can be observed using resistors  $R_{_{VCE2}} - R_{_{VCE11}}$ . In this example all resistors have a value of 100 k $\Omega$  and 1206 size and total value is 1 M $\Omega$ . These resistors should be chosen to conduct current between 0.6 mA to 0.8 mA at maximum DC-link voltage. The sum of  $R_{_{VCE2}} - R_{_{VCE11}}$  should be approximately 1 M $\Omega$  for 1200 V semiconductors and 500 k $\Omega$  for 600 V semiconductors. In each case the number of resistors and the package size has to be selected in a way to guarantee at least functional insulation between collector / drain and SCALE-iDriver. The low leakage diode  $D_{_{CL}}$  of BAS416 type, keeps the short-circuit duration constant over a wide DC-link voltage range.

Response time is set up through  $R_{_{VCE}}$  and  $C_{_{RES}}$  (typically 120 k $\Omega$  and 22 pF respectively for 1200 V semiconductors). If the short-circuit detection proves to be too sensitive, the  $C_{_{RES}}$  value can be increased. The maximum short-circuit duration must be limited to the maximum value given in the semiconductor data sheet.

Figure 10 illustrates the case where semiconductor desaturation is observed using diodes  $D_{vCE1}$  and  $D_{vCE2}$ . For insulation coordination purposes, two diodes of type STTH212U in a SMB package are used.  $R_{RES}$  connected to VISO guarantees current flow through the diodes when the semiconductor is in on-state. When the switch desaturates, the  $C_{RES}$  starts to be charged through  $R_{RES}$ . In this case the response time is given from the  $R_{RES}$  and  $C_{RES}$  values. In this application example  $C_{RES} = 33$  pF and  $R_{RES} = 62$  k $\Omega$ ; if desaturation is too sensitive or the short-circuit duration too long, both  $C_{RES}$  and  $R_{RES}$  can be adjusted.

Figure 11 shows a recommended PCB layout for the secondary-side (high-voltage) and corresponds to the schematic in Figure 10. The PCB consists of four layers, where top layer makes connection between assembled parts. Layer 2 is connected to the emitter of the IGBT's potential. Layer 3 is connected to  $V_{\rm ISO}$  potential and the bottom layer is connected to the potential of COM. It is important to note that layers two, three or the bottom layer must not cover the area below the desaturation diodes  $D_{\rm VCE1}$  and  $D_{\rm VCE2}$ . This is a critical design issue to avoid coupling capacitance with the SCALE-iDriver's VCE pin and insulation issues within the PCB.

Gate resistors are located physically close to the controlled semiconductor. As these components can get hot, it is recommended that they are placed away from the driver IC.

## **Short-Pulse Suppression**

Command signals applied to the IN pin (pin 7, V<sub>IN</sub>) are shorter than specified t<sub>GE(MIN</sub>, so the SCALE-iDriver output signals, GH and GL (pin 13 and pin 16), are extended to value t<sub>GE(MIN</sub>). The duration of pulses longer than t<sub>GE(MIN</sub> will not be changed.

## Soft Shut Down (SSD)

This function is activated after a short-circuit is detected. It protects the semiconductor against destruction by limiting the current slope in order to keep momentary V<sub>CE</sub> below V<sub>CES</sub> (semiconductor blocking voltage capability). Figure 12 shows the principle of the SSD function. The  $V_{cF}$  desaturation is visible during time period P1 (green line) and thanks to rail-to-rail SCALE-iDriver output stage technology, the  $V_{GE}$  (gate-emitter voltage, pink line) is kept very stable. After P1 (approximately 5  $\mu s)$  and according to note 15,  $V_{_{GE}}$  is limited to a lower value during a period specified as  $t_{ESD}$ . During  $t_{ESD}$  the short-circuit current slope is limited and initially a small overvoltage  $V_{CE}$  occurs. During time period P3, the gate of the semiconductor is being further discharged. Shortly before the discharging process is finished the gate-emitter is connected to  $-V_{\mbox{\tiny VEE}}.$  The remainder of the gate charge is removed, the short-circuit current is switched off and a second small  $\mathrm{V}_{\mathrm{ce}}$  overvoltage occurs. The whole short-circuit current detection and safe switch-off is lower than 10  $\mu$ s (7  $\mu$ s in this example).



Example

## GWJY]!Xf]jYf

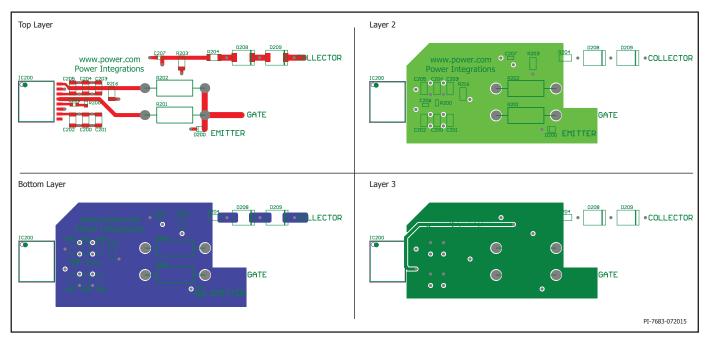


Figure 11. Recommended PCB Layout for Secondary-Side (High-Voltage). Corresponds to Schematic Shown in Figure 10.



